

Notice of References Cited	Application/Control No. 10/672,200	Applicant(s)/Patent Under Reexamination PARIKH ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,536,979 B1	03-2003	Kenny et al.	401/270
	B	US-6,132,445 A	10-2000	Pavanelli, Gianni	606/161
	C	US-4,415,288	11-1983	Gordon et al.	401/132
	D	US-6,070,286 A	06-2000	Cardarelli, Venanzio	15/167.1
	E	US-5,967,152 A	10-1999	Rimkus, Ronald J.	132/308
	F	US-5,133,971 A	07-1992	Copelan et al.	424/448
	G	US-5,098,297 A	03-1992	Chari et al.	433/215
	H	US-4,795,421	01-1989	Blasius et al.	604/1
	I	US-3,775,848	12-1973	Barnett, Edward M.	132/329
	J	US-3,672,378	06-1972	Silverman, Ralph H.	132/329
	K	US-4,451,164	05-1984	Roberts, Jr., James E.	401/196
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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